

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/039,383	CHU ET AL.
	Examiner S. Devi, Ph.D.	Art Unit 1645

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,846,477	01-2005	Keich et al.	424/9.1
*	B	US-5,695,769	12-1997	Frantz et al.	424/255.1
*	C	US-6,585,981	07-2003	Pijoan, Carlos	424/264.1
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	K	US-			
	L	US-			
	M	US-			

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	N	WO 02/10343	02-2002	PCT	Pijoan	
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NON-PATENT DOCUMENTS

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	U	Martinon et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 284. ✓
	V	Reynaud et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 150. ✓
	W	Charlier et al. In: Proc. 16th IPVS Congress. (Ed) Cargill et al. Melbourne, Australia, 17-20 September 2000, page 501. ✓
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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